

**Notice of References Cited**

Application/Control No. <b>09/461,756</b>		Applicant(s)/Patent Under Reexam <b>Kano</b>	
Examiner <b>B. William Baumeister</b>	Art Unit <b>2815</b>	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
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B	5,391,893	2/1995	Yamazaki	257	52
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**FOREIGN PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Sze, "Physics of Semiconductor Devices," 1981, John Wiley & Sons, Inc., pp. 743-760.
V	
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\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(e).

<sup>1</sup> Dates in MM-YYYY format are publication dates.

<sup>2</sup> Classifications may be U.S. or foreign.